

Search Notes

Application/Control No.

10/722,441

Examiner

James D. Stein

Applicant(s)/Patent under
Reexamination

KONDO, TAKAYUKI

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
385	14,15,24; 49	7/26/2005	JDS
398	141	7/26/2005	JDS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
385	14,24,49	7/26/2005	JDS
398	141	7/26/2005	JDS

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search History	7/26/2005	JDS
IEEE and INSPEC: substrate, tile, transmitter, receiver, emitter, detector, mux, demux, multiplex, waveguide, display,	7/26/2005	JDS
US-PGPUB interference search -- see attached EAST search history	7/26/2005	JDS